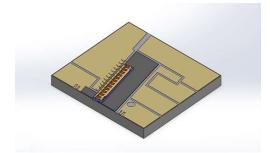
## **Specification**

Innolume GmbH Konrad-Adenauer-Allee 11 44263 Dortmund, Germany

# DFB12XX000CC100MXXXX

Distributed-Feedback (DFB) Laser Chip on Carrier



#### Features:

- Output power > 100mW ex-facet in 1200-1280nm range
- InAs/GaAs Quantum Dot based diode laser
- Proprietary mirror coating technology enabling high reliability
- Strong linear polarization
- RoHS compliance

#### **Applications:**

- Datacom
- Quantum and nonlinear optics
- Metrology and atomic references
- · Sensing and spectroscopy
- Testing and instrumentation

Recommended Operating Conditions				
@ CW, sample is mounted on a copper heatsink				
Parameter	Min.	Тур.	Max.	Unit
Heatsink Temperature	20	25*	40	°C
Forward Current		350	400	mA
Output Power**	5		100	mW

<sup>\*</sup> in some cases may vary depending on the selected wavelength

<sup>\*\*</sup> kink-free over the entire range

Characteristics				
@ CW, heatsink temperature 25°C*, 350mA				
Parameter	Min.	Тур.	Max.	Unit
Forward Current @ 100mW			400	mA
Forward Voltage @ 100mW		1.7	3.5	V
Threshold Current		50	90	mA
Peak Wavelength** (chosen by customer)	1200		1280	nm
Peak Wavelength Tolerance			±1	nm
Wavelength Temperature Tunability		120		pm/°C
Wavelength Current Tunability		2		pm/mA
Side-Mode Suppression Ratio (SMSR)	40	45		dB
Slow Axis Beam Divergence (FWHM)***	5	9	14	deg
Fast Axis Beam Divergence (FWHM)***	36	45	52	deg
Polarization Extinction Ratio (PER)	15	18		dB
Polarization		TE		

<sup>\*</sup> in some cases may vary in 20-40°C range depending on the selected wavelength

<sup>\*\*\*</sup> FF specified for all chip batches in 1200-1280nm range; more precise data available on request for specific chip batch

Chip parameters				
Parameter	Min.	Тур.	Max.	Unit
Chip length		2		mm
Back-reflection from Front Facet		0.001	0.01	%
Back-reflection from Back Facet		99		%

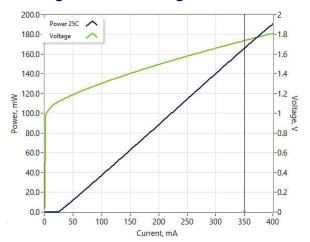
<sup>\*\*</sup> reachable within wavelength tolerance at power > 100mW

## **Specification**

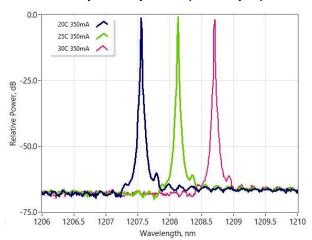
## Typical Performance (for reference only)

@ CW, recommended operating conditions

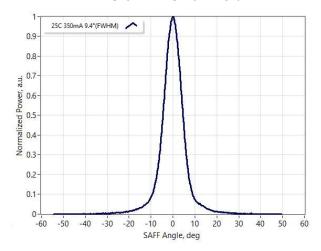
### **Light-Current-Voltage Characteristics**



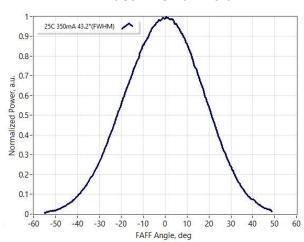
### **Optical Spectra (res. 10pm)**



### **Slow Axis Far Field**



### **Fast Axis Far Field**



Absolute Maximum Ratings			
Parameter	Min	Max	Unit
Forward Current		450	mA
Reverse Voltage		2	V
Operating Temperature (above dew point)	10	50	°C
Storage Temperature (in original hermetically sealed package)	-40	85	°C
Soldering Temperature (5 sec.max)		250	°C

44263 Dortmund, Germany



Dimensions (in mm) 107° ±1° 2.9 ±0.2 1111 Cathode (-) Output 05 ±0.03 90° ±1.5° Anode (+) 5.5 ±0.1 **DETAIL** A SCALE 60:1 95° ±0.5° 6 ±0.08 13 ±0.03 **Emitting Point** 

### Safety and Operating Instructions

The laser light emitted from this Device is invisible and harmful to the human eye. Avoid looking directly into the fiber output or into the collimated beam along its optical axis when the device is in operation. Proper laser safety eyewear must be worn during operation.

Absolute Maximum Ratings may be applied to the Device for short period of time only. Exposure to maximum ratings for extended period of time or exposure above one or more maximum ratings may cause damage or affect the reliability of the Device.

Operating the Device outside of its maximum ratings may cause device failure or a safety hazard. Power supplies used with the Device must be employed such that the maximum forward current cannot be exceeded. A proper heatsink for the Device on thermal radiator is required, sufficient heat dissipation and thermal conductance to the heatsink must be ensured by flux-free soldering. The use of thermal paste is prohibited.

Avoid back reflection to the device. It may give impact on the device performance in aspects of spectrum and power stability. It also may cause fatal facet damage. The use of optical isolators is mandatory to ensure stable operation by blocking back reflections.

The Device is an Open-Heatsink laser diode; it may be operated in cleanroom atmosphere or dust-protected housing only. Operating temperature and relative humidity must be controlled to avoid water condensation on the chip facets. Any contamination or contact of the chip facet must be avoided.

The performance of the Device (chip-on-carrier, chip on open-heatsink or bare die) is inherently dependent on the assembly process. When properly assembled, the Device can be expected to meet the specified performance characteristics. ESD PROTECTION - Electrostatic discharge is the primary cause of unexpected product failure. Take extreme precautions to prevent ESD. Use wrist straps, grounded work surfaces and rigorous antistatic techniques when handling the product.







# **Specification**

Innolume GmbH Konrad-Adenauer-Allee 11 44263 Dortmund, Germany

### **Part-number Identification**

DFB1200000CC100MXXXX -> 100mW output power at 1200nm peak wavelength, chip on carrier DFB1200D50CC100MXXXX -> 100mW output power at 1200.5nm peak wavelength, chip on carrier DFB1280000CC100MXXXX -> 100mW output power at 1280nm peak wavelength, chip on carrier

NOTE: Innolume product specifications are subject to change without notice